EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1126	(702/57-59).CCLS.	US-PGPUB; USPAT	OR	OFF	2007/05/15 08:39
L3	988	(702/81-84).CCLS.	US-PGPUB; USPAT	OR	OFF	2007/05/15 09:04
L4	906	(702/89,108).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/15 09:09
L5	1060	(702/117).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/15 09:12
L6	632	(702/118,119).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/15 09:18
L7	782	(702/120,121,123,125).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/15 09:18
L8	1320	(324/73.1).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/15 09:20
L9	287	(324/500,537,754,765).ccls. and parametric adj test$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:22
L10	59	(438/14,16,17).ccls. and parametric adj test$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:26
L11	101	(438/14,16,17).ccls. and (concurrent$2 simultaneous$2 synchronous$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:26
L12	0	(parametric and (test testing tested)).ti. and (load with wafer) same (automated or automatic$) and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:27
L13	8	parametric adj test$3 and (concurrent$2 simultaneous$2 synchronous$2 multitasking) with control and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:28
L14	2	parametric adj test$3 and (concurrent$2 simultaneous$2 synchronous$2 multitasking) with (controller controlling) and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:28
L15	0	parametric adj test$3 and (concurrent$2 simultaneous$2 synchronous$2 multitasking) with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:29

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L16	0	parametric adj test$3 and synchroniz$3 with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:29
L17	0	parametric adj test$3 and synchronization with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:29
L18	0	parametric adj test$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ$3 near (data instrumentation instrument) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:29
L19	0	parametric adj test$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ$3 near file and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:30
L20	0	parametric adj test$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same load near test and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:30
L21	0	parametric adj test$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ$3 near (data instrumentation instrument) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:30
L22	0	parametric adj test$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ$3 near file	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:31
L23	0	parametric adj test$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same load near test and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:31
L24	0	parametric adj test$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same load near test and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:31
L25	0	parametric adj test$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ$3 near memory	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:31
L26	0	parametric adj test$3 and state adj oscillator and @pd>"20060119"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:32
L27	0	state adj oscillator same fault-tolerant same test$3 and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:32
L28	0	state adj oscillator same fault-tolerant and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/05/15 09:32

L29	0	state adj oscillator same test$3 and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:32
L30	0	state adj oscillator same state near module and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:33
L31	0	state adj oscillator same state near object	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:33
L32	0	state adj oscillator same control adj state and @pd>"20060119"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:34
L33	0	state adj oscillator same superstate and @pd>"20060119"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:34
L34	2	parametric adj test$3 and (control controlling) adj state and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:34
L35	0	(wafer adj electrical adj (test testing)) with (move moving movement) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:34
L36	1	(semiconductor wafer) and (move moving movement prober alignment) with (simultaneous$2 concurrent$2) with (initialize initialized initialization) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:35
L37	0	parametric adj test$3 and concurrent adj operation and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:36
L38	0	parametric adj test$3 and simultaneous adj operation	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:36
L39	0	alignment with initialization with (concurrent$2 simultaneous$2) and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/15 09:36